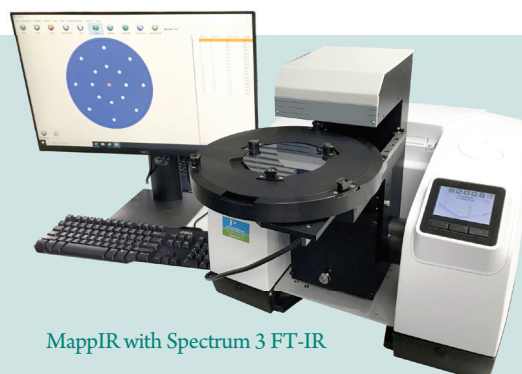


ASSURED QUALITY. ENGINEERED PERFECTION.

Confident Wafer Testing and Analysis with MappIR

Fabrication managers like you involved in wafer design and manufacturing are tasked with delivering efficient processes and high-quality production run rates that ultimately meet customer specifications and demands. You are often challenged with unreliable testing that results in production interruptions, lack of confidence, or with complex equipment that requires extensive training.

MappIR, in conjunction with our Spectrum 3™ FT-IR system, helps ensure quality, reduce fail rates, drive out impurities and deliver production results. Whether improving the final product uniformity and reducing glass-forming temperatures in front-end fabrication or evaluating and verifying doping levels to maintain and optimize production processes, MappIR delivers fast and high-quality results you can trust in an easy-to-use interface that requires minimal training.



MappIR with Spectrum 3 FT-IR

Front-End Fabrication

- Material identification
- Curing verification
- Testing to assess defects in chips
- Contaminant or particle detection

Back-End Assembly

- Final silicon wafer QA/QC testing
- Defect analysis

Learn more about wafer analysis with MappIR
at: www.perkinelmer.com/mappir

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